



### 12 2-

- R A T, 120, 140, 150, 200, 250, 300
- JEDEC A P  
32 , H , C , , 0.600" DIP  
(P 300)  
32 , H , C , , 0.400" SOJ  
(P 101)
- C , I , M, T  
R
- MIL-STD-883 C , D , A ,
- W, E 10,000 C
- D R , 25 C, 10 Y
- L P CMOS O ,

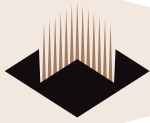
- A , P W, O ,  
I A D L 128 B  
I C T
- P W, C T 10 M .
- D P , E W, D ,
- H S D P ,
- TTL C , I O

This product is subject to change without notice.

1  
2  
2.4 I

NC	1	32	Vcc
A16	2	31	WE#
A15	3	30	NC
A12	4	29	A14
A7	5	28	A13
A6	6	27	A8
A5	7	26	A9
A4	8	25	A11
A3	9	24	OE#
A2	10	23	A10
A1	11	22	CS#
A0	12	21	I/O7
I/O0	13	20	I/O6
I/O1	14	19	I/O5
I/O2	15	18	I/O4
Vss	16	17	I/O3

A0-16	Address Inputs
I/O0-7	Data Input/Output
CS#	Chip Selects
OE#	Output Enable
WE#	Write Enable
Vcc	+5.0v Power
Vss	Ground



Parameter	Symbol	Min	Max	Unit
Operating Temperature	$T_A$	-55	+125	$^{\circ}\text{C}$
Storage Temperature	$T_{\text{STG}}$	-65	+150	$^{\circ}\text{C}$
Signal Voltage Relative to GND	$V_G$	-0.6	+6.25	V
Voltage on OE# and A9		-0.6	+13.5	V

## NOTE:

Stresses above those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

Parameter	Symbol	Min	Max	Unit
Supply Voltage	$V_{\text{CC}}$	4.5	5.5	V
Input High Voltage	$V_{\text{IH}}$	2.0	$V_{\text{CC}} + 0.3$	V
Input Low Voltage	$V_{\text{IL}}$	-0.5	+0.8	V
Operating Temp. (Mil.)	$T_A$	-55	+125	$^{\circ}\text{C}$
Operating Temp. (Ind.)	$T_A$	-40	+85	$^{\circ}\text{C}$

CS#	OE#	WE#	Mode	Data I/O
H	X	X	Standby	High Z
L	L	H	Read	Data Out
L	H	L	Write	Data In
X	H	X	Out Disable	High Z/Data Out
X	X	H	Write	
X	L	X	Inhibit	

 $T_A = +25^{\circ}\text{C}$ 

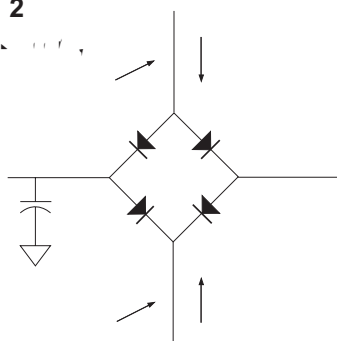
Parameter	Symbol	Condition	Min	Unit
Input Capacitance	$C_{\text{IN}}$	$V_{\text{IN}} = 0\text{ V}, f = 1\text{ MHz}$	20	pF
Output Capacitance	$C_{\text{OUT}}$	$V_{\text{IO}} = 0\text{ V}, f = 1\text{ MHz}$	20	pF

This parameter is guaranteed by design but not tested.

 $V_{\text{CC}} = 5.0\text{ V}, V_{\text{SS}} = 0\text{ V}, -55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$ 

Parameter	Symbol	Condition	Min	Max	Unit
Input Leakage Current	$I_{\text{LI}}$	$V_{\text{CC}} = 5.5, V_{\text{IN}} = \text{GND to } V_{\text{CC}}$		10	$\mu\text{A}$
Output Leakage Current	$I_{\text{LO}}$	$\text{CS\#} = V_{\text{IH}}, \text{OE\#} = V_{\text{IH}}, V_{\text{OUT}} = \text{GND to } V_{\text{CC}}$		10	$\mu\text{A}$
Operating Supply Current	$I_{\text{CC}}$	$\text{CS\#} = V_{\text{IL}}, \text{OE\#} = V_{\text{IH}}, f = 5\text{ MHz}, V_{\text{CC}} = 5.5$		80	mA
Standby Current	$I_{\text{SB}}$	$\text{CS\#} = V_{\text{IH}}, \text{OE\#} = V_{\text{IH}}, f = 5\text{ MHz}, V_{\text{CC}} = 5.5$		0.625	mA
Output Low Voltage	$V_{\text{OL}}$	$I_{\text{OL}} = 2.1\text{ mA}, V_{\text{CC}} = 4.5\text{ V}$		0.45	V
Output High Voltage	$V_{\text{OH}}$	$I_{\text{OH}} = -400\text{ }\mu\text{A}, V_{\text{CC}} = 4.5\text{ V}$	2.4		V

NOTE: DC test conditions:  $V_{\text{IH}} = V_{\text{CC}} - 0.3\text{ V}, V_{\text{IL}} = 0.3\text{ V}$



Parameter	Symbol	Unit
Input Pulse Levels	$V_{\text{IL}} = 0, V_{\text{IH}} = 3.0$	V
Input Rise and Fall	5	ns
Input and Output Reference Level	1.5	V
Output Timing Reference Level	1.5	V

Notes:  $V_Z$  is programmable from -2V to +7V.

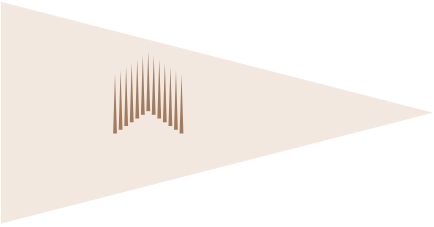
$I_{\text{OL}}$  &  $I_{\text{OH}}$  programmable from 0 to 16mA.

Tester Impedance  $Z_0 = 75\text{ }\Omega$ .

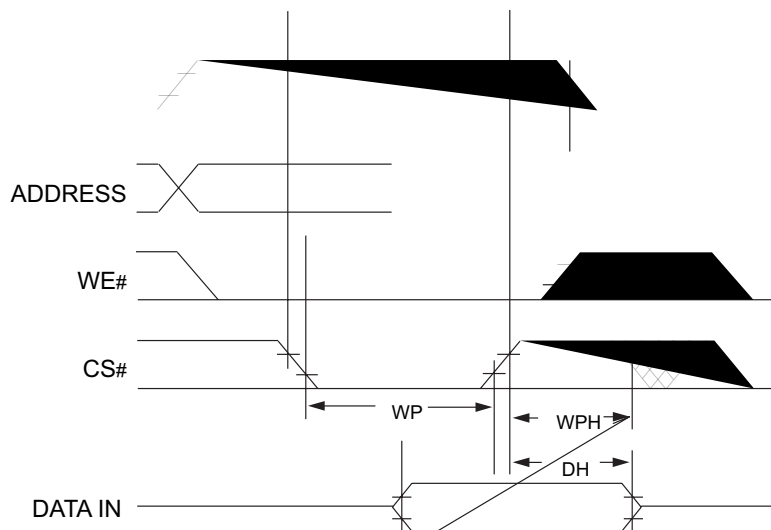
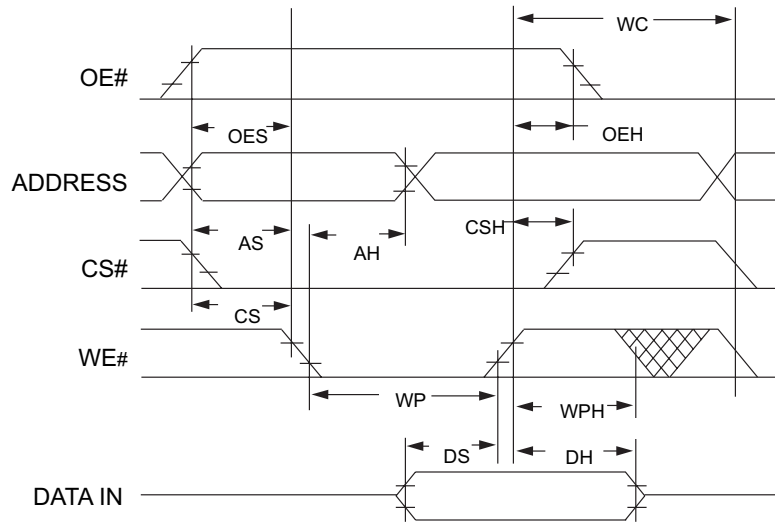
$V_Z$  is typically the midpoint of  $V_{\text{OH}}$  and  $V_{\text{OL}}$ .

$I_{\text{OL}}$  &  $I_{\text{OH}}$  are adjusted to simulate a typical resistive load circuit.

ATE tester includes jig capacitance.





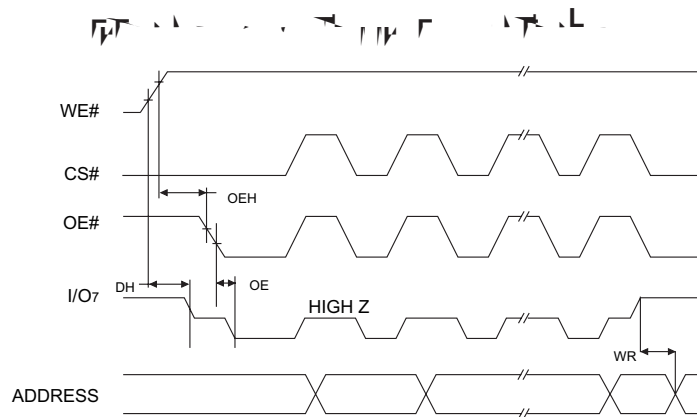




T WME128K8-XXX

$V_{CC} = 5.0V$ ,  $V_{SS} = 0V$ ,  $-55^{\circ}C$   $T_A$   $+125^{\circ}C$

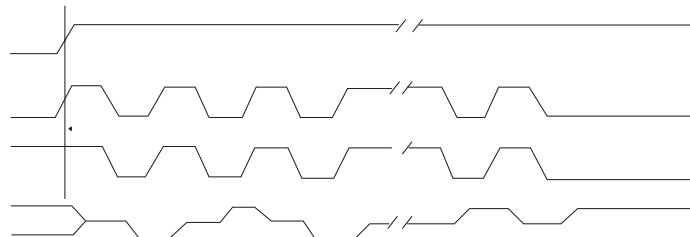
Pa a	\$ b	M	Ma	U
Data Hold Time	tdh	10		ns
OE# Hold Time	toeh	10		ns
OE# To Output Valid	toe		55	ns
Write Recovery Time	twr	0		ns



TOGGLE BIT: I DATA#P

(1)

\$ b	Pa a	M	Ma	U
tDH	Data Hold Time	10		ns
tOE	OE Hold Time	10		ns
tOEHP	OE High Pulse	150		ns
tWR	Write Recovery Time	0		ns



#### NOTE:

1. Toggling either OE# or CS# or both OE# and CS# will operate toggle bit.
2. Beginning and ending state of I/O6 will vary
3. Any address location may be used but the address should not vary.



T WME128K8-XXX  
128  
S  
f  
A  
150  
E  
T  
f

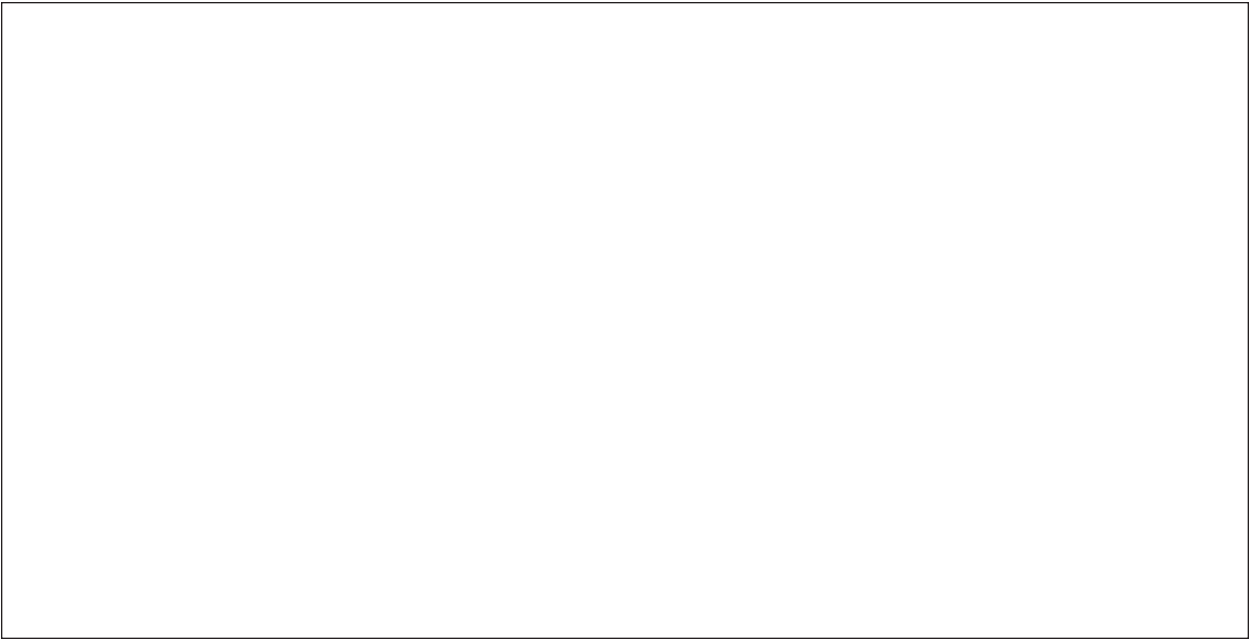
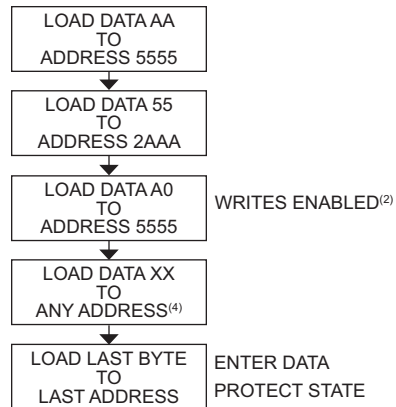





Figure 1-1. Load Data Sequence (1)



#### NOTES:

1. Data Format: I/O7 - I/O0 (Hex);  
Address Format: A<sub>16</sub> - A<sub>0</sub> (Hex).
2. Write Protect state will be activated at end of write even if no other data is loaded.
3. Write Protect state will be deactivated at end of write period even if no other data is loaded.
4. 1 to 128 bytes of data to be loaded.





LOAD DATA AA  
TO  
ADDRESS 5555

LOAD DATA 55  
TO  
ADDRESS 2AAA

LOAD DATA 80  
TO  
ADDRESS 5555

LOAD DATA AA  
TO  
ADDRESS 5555

LOAD DATA 55  
TO  
ADDRESS 2AAA

LOAD DATA 20  
TO  
ADDRESS 5555

LOAD DATA XX  
TO  
ANY ADDRESS<sup>(4)</sup>

LOAD LAST BYTE  
TO  
LAST ADDRESS

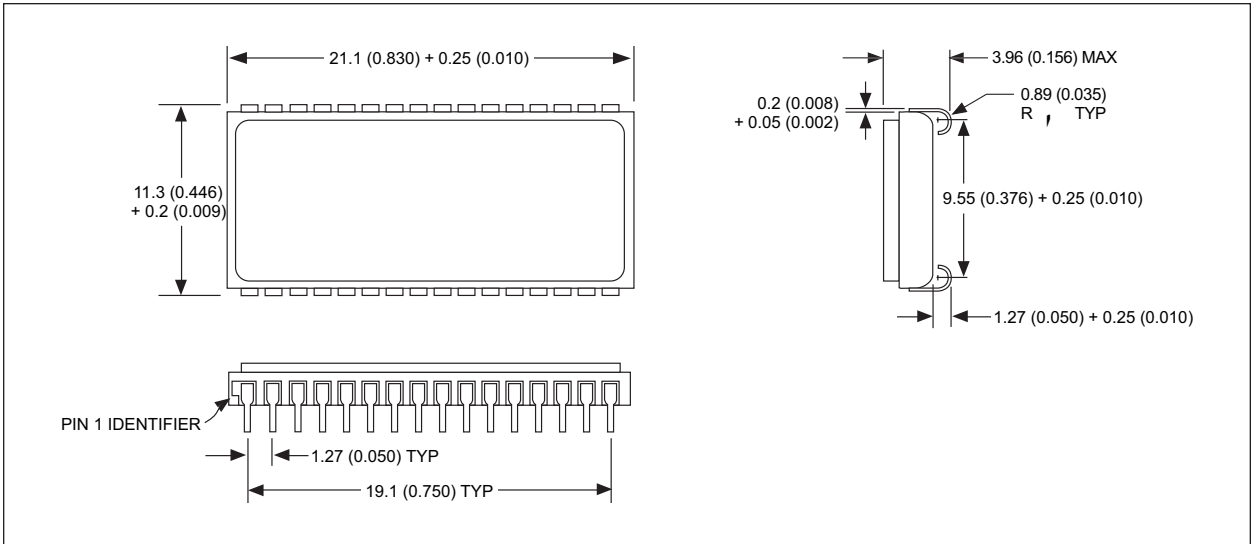
EXIT DATA  
PROTECT STATE<sup>(3)</sup>

### NOTES:

1. Data Format: I/O7 - I/O0 (Hex);  
Address Format: A16 - A0 (Hex).
2. Write Protect state will be activated at end of write even if no other data is loaded.
3. Write Protect state will be deactivated at end of write period even if no other data is loaded.
4. 1 to 128 bytes of data may be loaded.

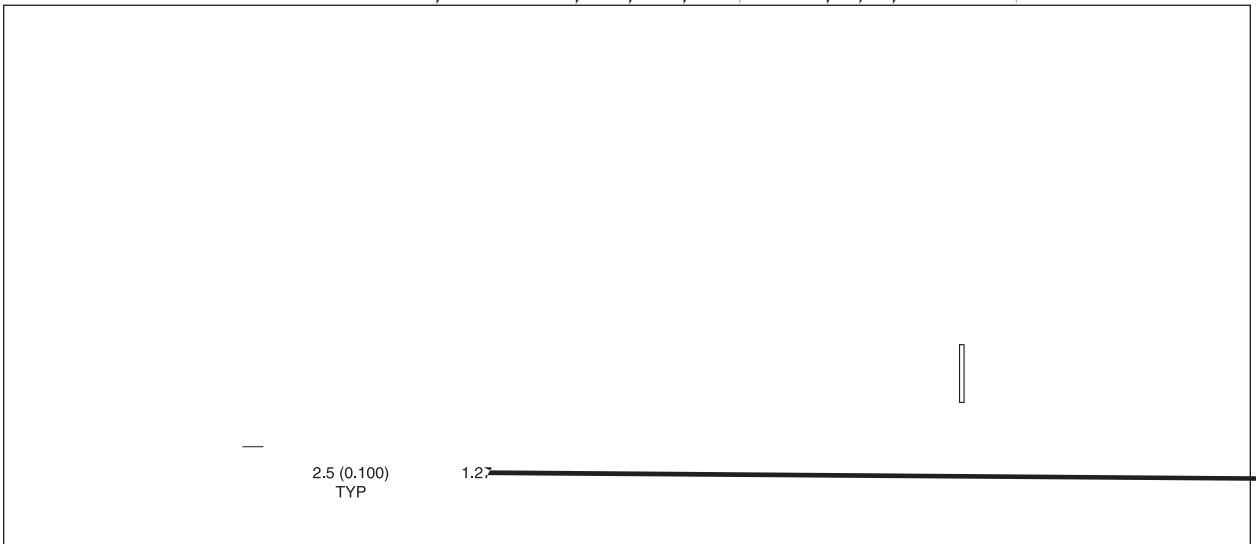


101 2



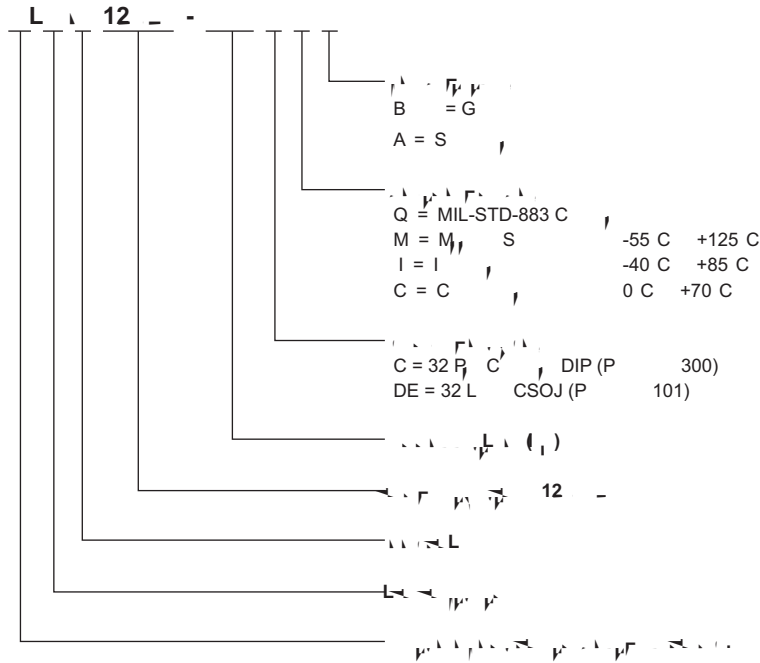
ALL LINEAR DIMENSIONS ARE MILLIMETERS AND PARENTHETICALLY IN INCHES

00 2





128K8-XXX



Part Number	Memory Type	Capacity	Package Type	Pin Count	Part Number
128K 8 EEPROM M	EEPROM	8K	DIP (C)	32	5962-96796 01HXX
128K 8 EEPROM M	EEPROM	8K	DIP (C)	32	5962-96796 02HXX
128K 8 EEPROM M	EEPROM	8K	DIP (C)	32	5962-96796 03HXX
128K 8 EEPROM M	EEPROM	8K	DIP (C)	32	5962-96796 04HXX
128K 8 EEPROM M	EEPROM	8K	DIP (C)	32	5962-96796 05HXX
128K 8 EEPROM M	EEPROM	8K	DIP (C)	32	5962-96796 06HXX
128K 8 EEPROM M	EEPROM	8K	SOJ (DE)	32	5962-96796 01HXX
128K 8 EEPROM M	EEPROM	8K	SOJ (DE)	32	5962-96796 02HXX
128K 8 EEPROM M	EEPROM	8K	SOJ (DE)	32	5962-96796 03HXX
128K 8 EEPROM M	EEPROM	8K	SOJ (DE)	32	5962-96796 04HXX
128K 8 EEPROM M	EEPROM	8K	SOJ (DE)	32	5962-96796 05HXX
128K 8 EEPROM M	EEPROM	8K	SOJ (DE)	32	5962-96796 06HXX